

PATTERN RECOGNITION LETTERS

Special Issue on Pattern Recognition in Remote Sensing

Submission Deadline: February 15, 2009

A Special Issue of the Pattern Recognition Letters journal (<http://www.elsevier.com/locate/inca/505619>) in the combined fields of **pattern recognition and remote sensing** will accept full journal papers up to February 15, 2009. This Special Issue is associated with the 5th IAPR Workshop on Pattern Recognition in Remote Sensing (PRRS 2008) that will take place on December 7, 2008 in Tampa, Florida as part of the prestigious International Conference on Pattern Recognition (ICPR 2008). Both PRRS and ICPR are sponsored by the International Association for Pattern Recognition (IAPR). PRRS 2008 is also sponsored by the IEEE Geoscience and Remote Sensing Society. PRRS workshops are implemented by IAPR Technical Committee 7 on Remote Sensing.

The PRRS Workshop has established itself as an important event for scientists involved in the combined fields of pattern recognition and remote sensing. These two research fields have always overlapped, but the large volumes of remote sensing data now coming from the last generation sensors require new advanced algorithms and techniques for automatic analysis. The workshop provides an ideal means to spread and exchange experiences by international researchers. However, to further advance this interdisciplinary science, a Special Issue on Pattern Recognition in Remote Sensing will be supported by Pattern Recognition Letters. The papers will encompass research that is interdisciplinary in the sense of applying novel pattern recognition techniques to unsolved problems in remote sensing image detection and analysis.

The objective of the Special Issue, **open to all researchers**, is to select outstanding contributions on recent advances in the combined fields of pattern recognition and remote sensing. The issue will be focused on the use of pattern recognition methods in the analysis of data collected from satellites or airborne sensors used for Earth observation. The special issue will include high quality papers presented at the workshop as well as other papers on the considered topic that are directly submitted to the special issue. All papers will undergo a peer review process in accordance with the requirements of the journal. Contributions are encouraged from professionals in research, industrial, and academic environments.

Prospective authors should follow the regular guidelines of the Pattern Recognition Letters journal, and should submit their manuscripts electronically to <http://ees.elsevier.com/patrec>. Please indicate during your submission that the paper is intended for this Special Issue by selecting "Special Issue PRRS 2008" from the pull-down menu for article type.

Inquiries with respect to the special issue should be directed to the Guest Editors:

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